Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HAN ET AL. | Examiner | Art Unit | Jason M. Han | 2875 | Page 1 of 1

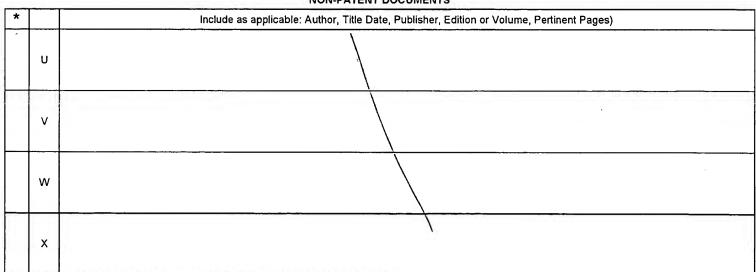
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	C	US-			
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	J	US-	-		
	K	US-		·	
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2000162593A	06-2000	Japan	Nishiyama et al.	G02F 1/1335
	0					
	Р					
	Q					
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